

Evaluating the effects of reducing voltage margins for energy-efficient operation of MPSoCs

Diego V. Cirilo do Nascimento, Kyriakos Georgiou, Kerstin I. Eder and Samuel Xavier-de-Souza

Abstract—Voltage margins, or guardbands, are imposed on DVFS systems to account for process, voltage, and temperature variability effects. While necessary to assure correctness, guardbands reduce energy efficiency, a crucial requirement for embedded systems. The literature shows that error detection techniques can be used to maintain the system’s reliability while reducing or eliminating the guardbands. This letter assesses the practically available margins of a commercial RISC-V MPSoC while violating its guardband limits. The primary motivation of this work is to support the development of an efficient system leveraging the redundancy of multicore architectures for an error detection and correction scheme capable of mitigating the errors caused by aggressive voltage margin reduction. For an equivalent performance, we achieved up to 27% energy reduction while violating the manufacturer’s defined guardband, leaving reasonable energy margins for further development.

Index Terms—energy, undervolting, overclocking, guardband

I. INTRODUCTION

ENERGY efficiency is crucial for mobile and embedded systems, where battery size, autonomy, and power dissipation are under hard constraints. Such systems must comply with these limitations while being capable of delivering the high performance needed by demanding Edge Computing and IoT devices [1].

The supply voltage significantly impacts the total power consumption, hence should be kept at a minimum. Signal propagation delays, however, are inversely proportional to the operating voltage and are a limiting factor for the maximum clock frequency [2].

Dynamic voltage and frequency scaling (DVFS) techniques have been developed as means to meet processing requirements at minimal power dissipation [3]. These operating voltage/frequency points are defined *a priori* and must comply with critical-path timing limitations [4]. The critical path delays are affected by process, voltage, and temperature (PVT) variability, so safety voltage margins or “guardbands” are imposed on the DVFS system, assuring a reliable operation. Critical path violation errors may occur if the system is otherwise allowed to run too close to the physical limits. Ongoing miniaturization increases variability during chip manufacture, and these guardbands are vital for lower technology nodes. Consequently, the addition of voltage guardbands trades energy efficiency for correctness [5].

Several approaches have been proposed to reduce these margins, broadly divided into “always-correct” and error-detection-based methodologies.

In “always-correct” methodologies, the chip never enters an unsafe operating point. Notable examples use critical-path-equivalent, or “canary”, circuits to assess the timing constraints on-the-fly and provide adaptive voltage scaling, reducing design-time defined margins [6]. Besides the power and area overhead, a drawback of this approach is that local variability in process and power supply distribution across the chip cannot be accounted for, thus still requiring considerable voltage margins.

On the more aggressive voltage reduction path, error-detection-based circuits, such as Razor [7], [8], use special delayed-path flip-flops to detect and correct timing failures. These failures are then reported and used for adaptive voltage scaling. The main advantage is that the voltage guardbands are effectively removed at the expense of deep circuit modifications, which add design and verification overheads, limiting its application in existing designs.

Bacha and Teodorescu [9] proposed a less intrusive architectural approach, leveraging the existing Error Detection and Correction (EDAC) hardware in Intel Itanium processors for voltage margin elimination. The system is allowed to run in a configuration susceptible to timing errors but is kept functional by relying on the EDAC features. By keeping the system at an operating point where the error rate is low enough, the energy gains surpass the recovery costs with a negligible performance penalty.

In embedded Multi-processor System-on-Chip (MPSoC) devices where EDAC features are not readily available, the inherent core redundancy can be leveraged in fault-tolerant arrangements [10], [11], which can potentially be exploited to reduce voltage margins. This may enable energy efficiency gains for applications that would otherwise be unsuitable for parallelization.

In the interest of assessing the viability of using MPSoC core-redundancy EDAC schemes for voltage guardband reduction, this letter presents characterization experiments of a commercial MPSoC, the Greenwaves Technologies GAP8. This characterization consists of violating the published manufacturer’s voltage guardbands by overclocking the chip and measuring the available energy margins and practical voltage/frequency limits.

In our experiments, frequencies up to $2.5\times$ higher than those specified in the datasheet were achieved before any errors or lockups were detected. When comparing performance-equivalent operating points, we were able to reduce the energy

D. V. C. do Nascimento is with Instituto Federal do Rio Grande do Norte - IFRN, Natal-RN, Brazil.

K. Georgiou and K. I. Eder are with the University of Bristol, UK.

S. Xavier-de-Souza is with Universidade Federal do Rio Grande do Norte - UFRN, Natal-RN, Brazil.

by 27%, confirming that margins are available for implementing an error detection and correction scheme to ensure reliability and energy efficiency in these extreme settings.

In the rest of the text, Section II presents related works and supporting literature data, Section III presents the experimental methodology, Section IV details the results, and Section V contains our conclusions.

II. RELATED WORKS

Two main topics are of interest to this letter, aggressive voltage margin elimination and error detection methods in multiprocessor chips.

A. Voltage margins elimination

Bacha and Teodorescu [9] used a firmware-based solution on an Intel Itanium 9560, aggressively reducing operating voltage until the on-chip EDAC system started reporting recoverable errors. Actively controlling the voltage to keep the error rate between set boundaries, they achieved an average reduction of 20% in power consumption, with an error-recovery time overhead of less than 1%. In a subsequent paper, a more efficient approach, with dedicated hardware targeting sensitive cache lines, achieved a power reduction of 33% [12].

Leng et al. [13] reduced voltage margins in NVIDIA GPUs by predicting the V_{\min} , or minimal error-free voltage. Based on the observation that this V_{\min} primarily depends on voltage droops caused by software operation, i.e., the available margins are application dependent, they derived a prediction scheme based on the analysis of performance counters. They found that voltage can be reduced by up to 20% without errors.

Papadimitriou et al. [14], [15] exploited the available margins at multiple platforms in a series of papers, using available EDAC hardware error reporting as a guideline. They ran benchmarks from the SPEC2600 suite and collected information about multiple margins, from error-free operation up to system lockup. By reducing the voltage margins, they achieved power savings of 18% in ARMv8 processors, 20% in Intel processors, 25% on NVIDIA Fermi and Kepler GPUs, and up to 90% for FPGA on-chip memories [16].

In our review, no equivalent tests were performed on MP-SoCs, probably due to the lack of EDAC features in devices readily available on the market.

B. Error detection in MPSoCs

Simevski et al. [10] investigated the usage of idle cores in multiprocessors for N-modular redundancy schemes. Subsequently, they developed the Waterbear framework, a fault-tolerant multicore architecture with switchable operating modes, using parallelism or redundancy-based fault-tolerance on demand.

Silva et al. [11] presented the CEVERO architecture, a fault-tolerant MPSoC based on the open-source PULP Platform [17]. This architecture uses a switchable Dual-Modular Redundancy (DMR) scheme aided by “safe” status registers, which can return the cores to the last known-good state and resume operation.

TABLE I
GAP8 GUARD BAND VALUES [19].

Voltage	FC_{\max}	$Cluster_{\max}$
1200 mV	250 MHz	170 MHz
1150 mV	225 MHz	149 MHz
1100 mV	200 MHz	129 MHz
1050 mV	175 MHz	108 MHz
1000 mV	150 MHz	87 MHz

Rogenmoser et al. [18] developed an On-Demand Redundancy Grouping (ODRG) scheme for the PULP platform, where cores in a cluster can be arranged either for parallel computing or fault-tolerant mode, running a Triple Modular Redundancy (TMR) block with three cores in lockstep. Their approach uses a voter, maintaining execution in the event of a mismatch in the output of one of the cores and later synchronizing the faulty core.

Both Waterbear and ODRG approaches need three cores for error recovery. In comparison, the CEVERO architecture uses two cores and extra state registers, saving on area and power consumption at the cost of a minor performance penalty during the recovery process.

Our present work aims to complement Silva’s work, exploiting its fault tolerance features to save energy.

III. EXPERIMENTAL METHODOLOGY

Using a PULP-based MPSoC, two experiments were arranged, one for detecting computation errors and lockups while exceeding the published voltage and frequency guardbands and the other using a real-world application to measure energy consumption in extreme settings. The goal was to assess the available margins for these use cases, serving as supporting evidence for the future development of an error-detection-based methodology to reduce voltage margins.

A. Hardware Setup

The base hardware is the Greenwaves Technologies GAP8, a commercial implementation of the PULP’s Mr. Wolf [17] chip. The main benefits of using this architecture are the open nature of most of the design, facilitating further development, modularity, and state-of-the-art energy efficiency features. It is composed of a Fabric Controller (FC) core and an eight-core cluster. The FC and Cluster are on separated clock domains, which can be controlled by an on-chip Frequency Locked Loop (FLL) device. The system also has an onboard DC-DC converter able to supply voltages from 1.0V up to 1.2V in 50mV steps. Table I shows the datasheet guardbands.

A GAP8 development board, called *Gapuino*, is used to provide hardware support, external power supply and communications, and test points for voltage and current measurements.

B. Measurements

A GPIO port is used as a trigger to start the time and power measurement. The measurements are performed using a MAGEEC Power Measurement board[20], based on ST Discovery STM32F407VG. The power is measured by a shunt

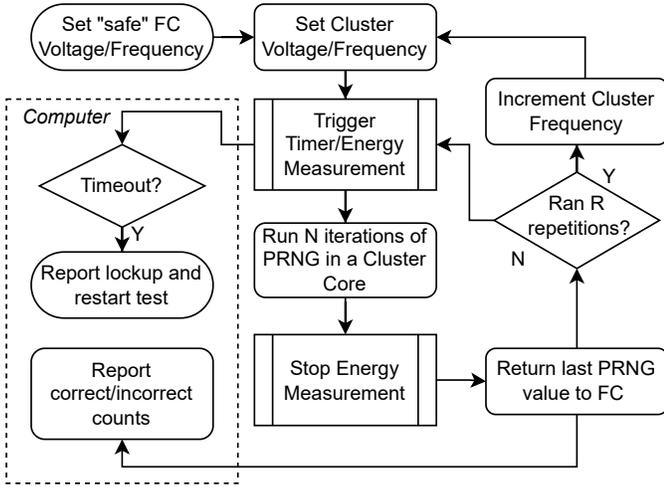


Fig. 1. Test flowchart.

resistor available at the GAP8 power supply path, isolated from the rest of the board but including the on-chip DC-DC converter. The energy of the operation is calculated using execution time and average power.

C. Experiment A setup

For the first experiment, a pseudorandom number generator (PRNG) was used as workload, generating sequences of N numbers in variable frequency/voltage settings. A flowchart of the test can be seen in Figure 1.

We proposed this workload due to its susceptibility to data corruption, deviating the output sequence in the event of any error in the calculations. To counter the lack of hardware error-detection capabilities, periodic checking of the results was necessary, comparing the last value of the generated sequence with known-good values. Any mismatch in these values results from calculation or memory errors during the execution.

The test control happens in the FC core, which is set as a “safe” core, and the PRNG is run in a Cluster core, where the clock can be set to extreme values independently.

After each R run, the last value is returned to be compared to the reference. If different, the test is flagged as an error. The test is flagged as a lockup if no response is received after a timeout.

The tests were run for all available voltages and frequencies starting at 200MHz, increasing in 2 MHz steps, until the chip stopped responding. The starting frequency was decided empirically in preliminary tests, where errors only started to occur beyond this frequency, even for the lowest voltage.

For any given frequency/voltage pair, the test was run with increasing problem sizes, from 50K to 1M numbers in 50K steps, to check if error probability was related to runtime. The test duration depended on the problem size and set frequency, ranging from approximately 35ms to 32 seconds.

A total number of 678440 tests were executed.

D. Experiment B setup

For the real-world application, we used a satellite communication algorithm developed by De Lima *et al.* [21] for the GAP8 platform. This algorithm runs in parallel, using all eight cores of the cluster, and performs multiple operations, including data movement and integer FFT.

The tests ran in all available voltage levels and frequencies ranging from 80MHz, inside the guardband for all voltages, to 200MHz, outside the guardband for all voltages.

IV. RESULTS

Figure 2 presents the error and lockup figures of the whole dataset, with a guardband reference line at the bottom of the graph. It is possible to observe that, apart from a few outliers, the failures occur in a narrow band, without much margin between the point where the error rate starts to rise and the total loss of response. The error probability did not grow with the problem size, being primarily dependent on the critical operating points. Hence the narrow failure points distribution shown in Figure 2. As the voltage increases, the lockups start to occur before the errors are detected. The data shows a tendency that for lower voltages the errors start to happen at even lower voltages than the lockups, probably due to the critical path violations being the primary source of errors.

In any case, from the guardband to the minimum value, we have at least two times the clock frequency, reaching $2.5\times$ for the lowest tested voltage (1V).

Being able to reach higher frequencies for the same voltage can be translated to reduced energy consumption as execution times decrease. With the proper hardware setup, this relation can be exploited, reducing the voltage while respecting applications’ timing requirements.

The errors and lockups can be mitigated by EDAC methodologies, and the error rate can be used to control an active voltage scaling scheme.

For Experiment B, Figure 3 presents the energy consumption characteristic of the circuit for a given performance. Up to 27% of energy can be saved by overclocking the system, as the time reduction compensates for the power increase.

The flattening of the energy consumption between the 1.15V and 1.2V settings is probably due to power circuitry effects. We are not able to measure the core voltages, but this voltage change can be confirmed by the increased maximum “error-free” frequency.

V. CONCLUSION

This letter presented experiments characterizing the GAP8 MPSoC when violating the manufacturer-defined voltage guardband, providing evidence and motivation for developing novel guardband reduction techniques.

For multicore architectures, the inherent redundancy of cores can be exploited in a fault-tolerant arrangement, which in turn can be used to warrant correct operation in guardband-violating settings. These extreme settings can improve energy efficiency, for example, in applications unfit for parallelization.

The energy reduction of about 27% achieved in the experiments provides a target consumption for the complete

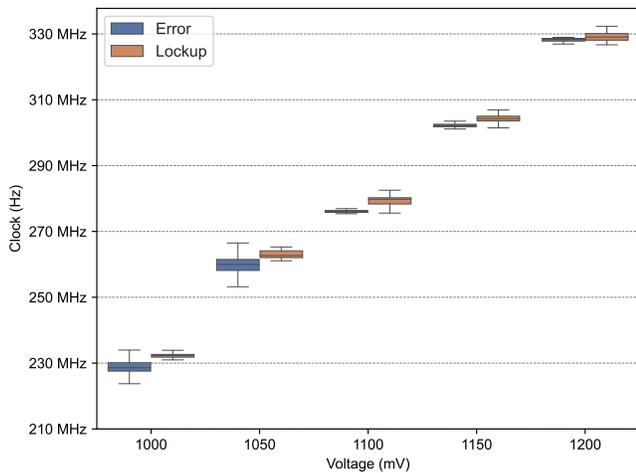


Fig. 2. Error and lockup distribution.

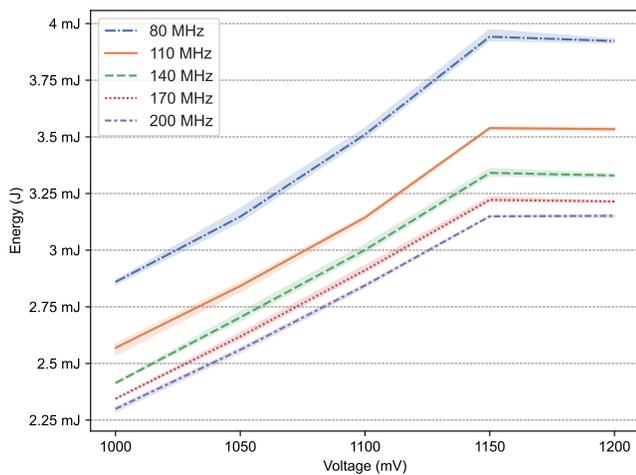


Fig. 3. Energy consumption of SBCDA decoder.

system. We can expect greater gains if we consider that the maximum energy reduction was in a “safe” configuration for the energy measurement experiment as no fault-tolerant system was employed. Therefore, considering the failure threshold shown in Experiment A, there are still higher margins to be harvested. Additionally, due to the limitation of the on-chip DC-DC converter, it was not possible to go lower than 1V, where there is a tendency to increase efficiency, as shown in Figure 3.

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